

OptiMOS[™]3 Power-Transistor

Features

- Fast switching MOSFET for SMPS
- Optimized technology for DC/DC converters
- Qualified according to JEDEC¹⁾ for target applications
- N-channel, normal level
- Excellent gate charge x R_{DS(on)} product (FOM)
- ullet Very low on-resistance $R_{\,\mathrm{DS(on)}}$
- 100% Avalanche tested
- Pb-free plating; RoHS compliant
- Halogen-free according to IEC61249-2-21

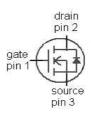
Product Summary

V_{DS}	40	V
$R_{\mathrm{DS(on),max}}$	4.1	mΩ
I _D	80	Α





Туре	IPB041N04N G	IPP041N04N G
	1 3 2 (tab)	123
Package	PG-TO263-3	PG-TO220-3
Marking	041N04N	041N04N



Maximum ratings, at T_i =25 °C, unless otherwise specified

Parameter	Symbol	Conditions	Value	Unit
Continuous drain current	I _D	$V_{\rm GS}$ =10 V, $T_{\rm C}$ =25 °C	80	Α
		V _{GS} =10 V, T _C =100 ℃	80	
Pulsed drain current ²⁾	I _{D,pulse}	T _C =25 ℃	400	
Avalanche current, single pulse ³⁾	IAS	T _C =25 ℃	80	
Avalanche energy, single pulse	E _{AS}	$I_{\rm D}$ =80 A, $R_{\rm GS}$ =25 Ω	60	mJ
Gate source voltage	V _{GS}		±20	V

¹⁾ J-STD20 and JESD22



Maximum ratings, at T_j =25 $^{\circ}$ C, unless otherwise specified

Parameter	Symbol	Conditions	Value	Unit
Power dissipation	P_{tot}	T _C =25 ℃	94	W
Operating and storage temperature	$T_{\rm j},T_{\rm stg}$		-55 175	C
IEC climatic category; DIN IEC 68-1			55/175/56	

Parameter	Symbol	Conditions		Values		Unit
			min.	typ.	max.	

Thermal characteristics

Thermal resistance, junction - case	R_{thJC}		-	-	1.6	K/W
SMD version, device on PCB	$R_{ m thJA}$	minimal footprint	-	-	62	
		6 cm² cooling area ⁴⁾	-	-	40	

Electrical characteristics, at T_j =25 $^{\circ}$ C, unless otherwise specified

Static characteristics

Drain-source breakdown voltage	$V_{(BR)DSS}$	V _{GS} =0 V, I _D =1 mA	40	-	-	V
Gate threshold voltage	$V_{\rm GS(th)}$	$V_{\rm DS}=V_{\rm GS}$, $I_{\rm D}=45~\mu{\rm A}$	2	-	4	
Zero gate voltage drain current	I _{DSS}	$V_{\rm DS}$ =40 V, $V_{\rm GS}$ =0 V, $T_{\rm j}$ =25 °C	ı	0.1	1	μΑ
		$V_{\rm DS}$ =40 V, $V_{\rm GS}$ =0 V, $T_{\rm j}$ =125 °C	-	10	100	
Gate-source leakage current	I _{GSS}	V _{GS} =20 V, V _{DS} =0 V	-	10	100	nA
Drain-source on-state resistance ⁵⁾	R _{DS(on)}	V _{GS} =10 V, I _D =80 A	-	3.3	4.1	mΩ
Gate resistance	R _G		-	1.6	-	Ω
Transconductance	g_{fs}	V _{DS} >2 I _D R _{DS(on)max} , I _D =80 A	50	100	-	s

 $^{^{2)}}$ See figure 3 for more detailed information

³⁾ See figure 13 for more detailed information

 $^{^{4)}}$ Device on 40 mm x 40 mm x 1.5 mm epoxy PCB FR4 with 6 cm2 (one layer, 70 μ m thick) copper area for drain connection. PCB is vertical in still air.

⁵⁾ Measured from drain tab to source pin



Parameter	Symbol	Conditions		Values		Uni
			min.	typ.	max.	
Dynamic characteristics						
Input capacitance	C _{iss}		-	3400	4500	pF
Output capacitance	Coss	$V_{\rm GS}$ =0 V, $V_{\rm DS}$ =20 V, f =1 MHz	-	980	1300	
Reverse transfer capacitance	C _{rss}]	-	36	-	1
Turn-on delay time	$t_{d(on)}$		-	16	-	ns
Rise time	t _r	V _{DD} =20 V, V _{GS} =10 V,	-	3.8	-	1
Turn-off delay time	$t_{\text{d(off)}}$	I_{D} =30 A, R_{G} =1.6 Ω	-	23	-	1
Fall time	t_{f}]	-	4.8	-	1
Gate Charge Characteristics ⁶⁾	•					
Gate to source charge	Q _{gs}		•	18	-	nC
Gate charge at threshold	Q _{g(th)}		-	10.3	-	
Gate to drain charge	Q _{gd}	V _{DD} =20 V, I _D =30 A,	-	5.3	-]
Switching charge	Q _{sw}	V _{GS} =0 to 10 V	-	12.5	-	1
Gate charge total	Qg]	-	42	56	1
Gate plateau voltage	V _{plateau}]	-	5.1	-	V
Gate charge total, sync. FET	Q _{g(sync)}	V _{DS} =0.1 V, V _{GS} =0 to 10 V	-	40	-	nC
Output charge	Q _{oss}	V _{DD} =20 V, V _{GS} =0 V	-	41	-	1
Reverse Diode	•					
Diode continuous forward current	Is	-7 _C =25 ℃	-	-	78	А
Diode pulse current	I _{S,pulse}	7 _C =20 C	-	-	400	
Diode forward voltage	V_{SD}	$V_{\rm GS} = 0 \text{ V}, I_{\rm F} = 80 \text{ A}, T_{\rm j} = 25 \text{ C}$	-	0.96	1.2	V
Reverse recovery charge	Q _{rr}	V_R =20 V, I_F = I_S , di_F/dt =400 A/ μ s	-	46	-	nC

⁶⁾ See figure 16 for gate charge parameter definition

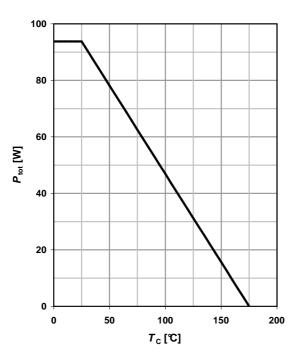


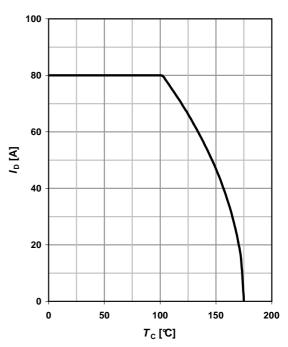
1 Power dissipation

$P_{\text{tot}} = f(T_{\text{C}})$

2 Drain current

$$I_D=f(T_C); V_{GS} \ge 10 \text{ V}$$





3 Safe operating area

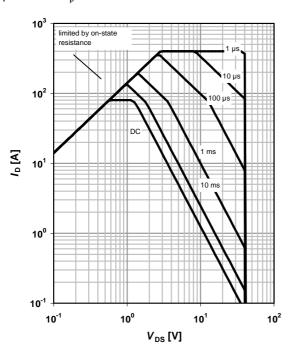
$$I_D=f(V_{DS}); T_C=25 \text{ } \text{C}; D=0$$

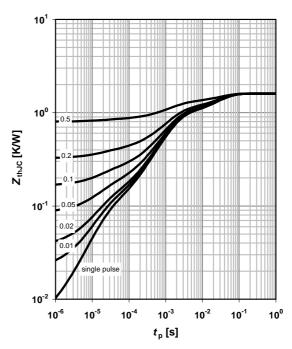
parameter: t_p

4 Max. transient thermal impedance

$$Z_{\text{thJC}} = f(t_p)$$

parameter: $D=t_p/T$



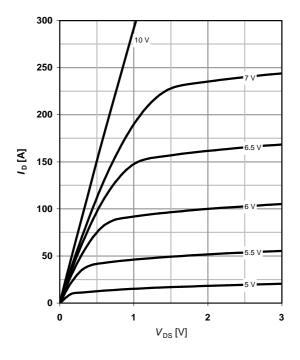




5 Typ. output characteristics

 $I_D=f(V_{DS}); T_j=25 \text{ } \text{C}$

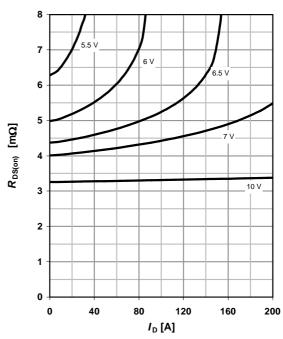
parameter: V_{GS}



6 Typ. drain-source on resistance

 $R_{DS(on)}=f(I_D); T_j=25 \text{ } \text{C}$

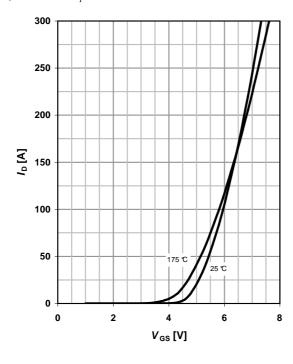
parameter: V_{GS}



7 Typ. transfer characteristics

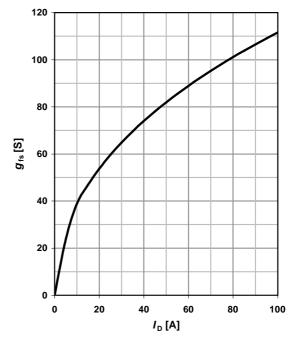
 I_{D} =f(V_{GS}); $|V_{DS}|$ >2 $|I_{D}|R_{DS(on)max}$

parameter: $T_{\rm j}$



8 Typ. forward transconductance

 $g_{fs}=f(I_D); T_j=25 \text{ } \text{C}$



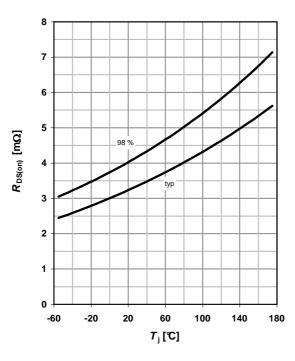


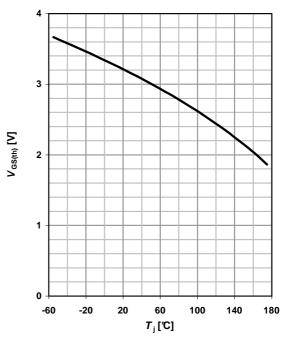
9 Drain-source on-state resistance

$R_{DS(on)}$ =f(T_j); I_D =80 A; V_{GS} =10 V

10 Typ. gate threshold voltage

$$V_{GS(th)}$$
=f(T_j); V_{GS} = V_{DS} ; I_D =250 μ A



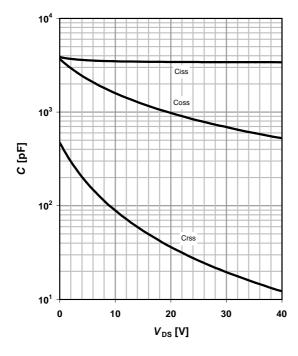


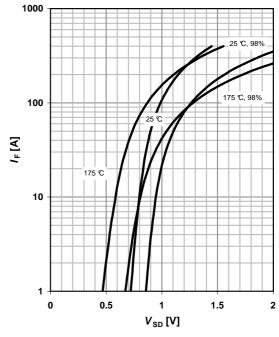
11 Typ. capacitances

$$C=f(V_{DS}); V_{GS}=0 V; f=1 MHz$$

12 Forward characteristics of reverse diode

 I_{F} =f(V_{SD})
parameter: T_{j}



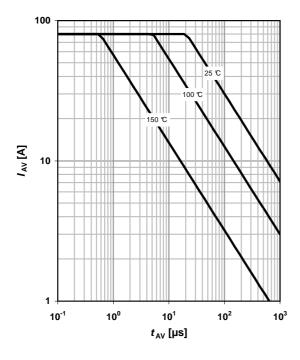




13 Avalanche characteristics

 I_{AS} =f(t_{AV}); R_{GS} =25 Ω

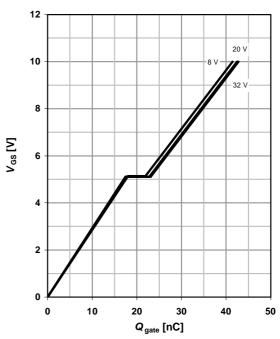
parameter: $T_{j(start)}$



14 Typ. gate charge

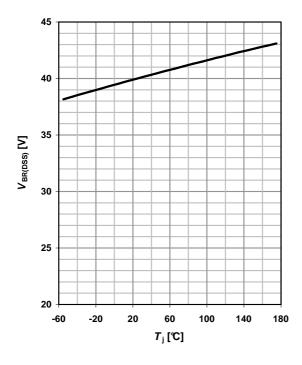
 V_{GS} =f(Q_{gate}); I_D =30 A pulsed

parameter: $V_{\rm DD}$

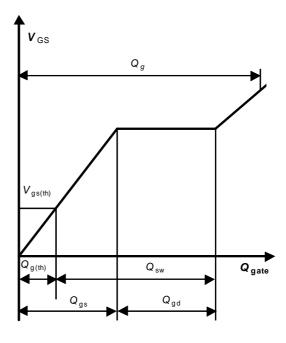


15 Drain-source breakdown voltage

 $V_{BR(DSS)}=f(T_j); I_D=1 \text{ mA}$



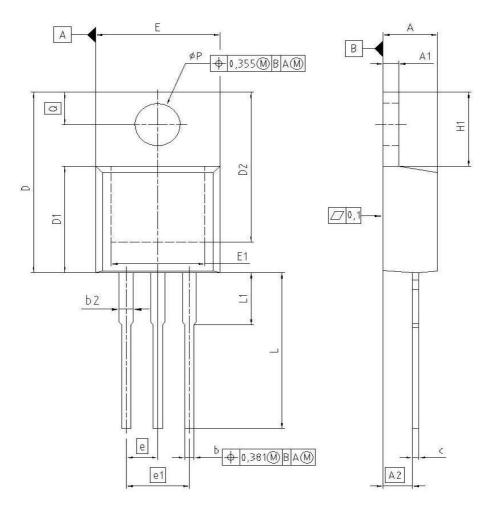
16 Gate charge waveforms





Package Outline

PG-TO220-3-1



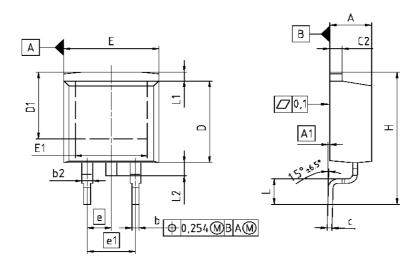
DIM	MILLIM	ETERS	INC	HES
DIN	MIN	MAX	MIN	MAX
Α	4.300	4.572	0.169	0.180
A1	1.170	1.400	0.046	0.055
A2	2.215	2.718	0.087	0.107
b	0.650	0.864	0.026	0.034
b2	0.635	1.778	0.025	0.070
C	0.330	0.600	0.013	0.024
D	14.808	15.950	0.583	0.628
D1	8.509	9.450	0.335	0.372
D2	12.850	13.100	0.506	0.516
E	9.700	10.363	0.382	0.408
E1	6.500	8.600	0.256	0.339
e	2.5	540	0.1	100
e1	5.080		0.2	200
N		3		3
H1	5.900	6.900	0.232	0.272
L	13.000	14.000	0.512	0.551
L1	4	4.800	j u	0.189
pΡ	3.700	3.886	0.146	0.153
Q	2.600	3.000	0.102	0.118

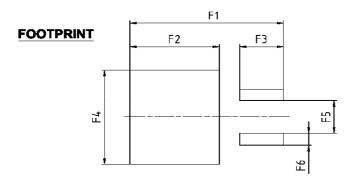
REFERE	NCE
JEDEC T	O220
SCALE	0-
0 2.5 luunuulu	2.5 5mm
EUROPEAN PI	ROJECTION
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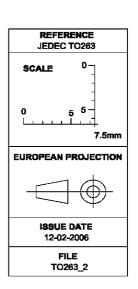
Package Outline

PG-TO263-3





DIM	MILLIMI	ETERS	INC	1ES
DIM	MIN	MAX	MIN	MAX
Α	4.300	4.572	0.169	0.180
A1	0.000	0.254	0.000	0.010
ь	0.650	0.850	0.026	0.033
b2	0.950	1.321	0.037	0.052
С	0.330	0.650	0.013	0.026
¢2	0.170	1.400	0.046	0.055
D	8.509	9.450	0.335	0.372
D1	7.100	-	0.280	-
E	9.800	10.312	0.386	0.406
E1	6.500		0.256	
•	2.540		0.100	
e1	5.080		0.200	
N	2			2
Н	14.605	15.875	0.575	0.625
L	2.200	3.000	0.087	0.118
L1	-	1.600	-	0.063
L2	1.000	1.778	0.039	0.070
F1	1 6.05 0	16.250	0.632	0.640
F2	9.300	9.500	0.366	0.374
F3	4.500	4.700	0.177	0.185
F4	10.700	10.900	0.421	0.429
F5	3.630	3.830	0.143	0.151
F6	1.100	1.300	0.043	0.051





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